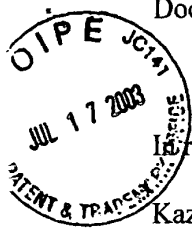


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2851-
\$

Docket No. WAK.059

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Kazuki Yokota

Serial No.: 09/627,456 ✓

Group Art Unit: 2851 ✓

Filed: July 27, 2000

Examiner: Cruz, Magda

For: OVERLAY MARK, METHOD OF MEASURING OVERLAY ACCURACY,
METHOD OF MAKING ALIGNMENT AND SEMICONDUCTOR DEVICE
THEREWITH

Honorable Commissioner of Patents
Alexandria, Virginia 22313-1450

EXCESS CLAIM FEE PAYMENT LETTER

Sir:

Transmitted herewith is an amendment in the above-identified application. The fee has been calculated and is transmitted as shown below.

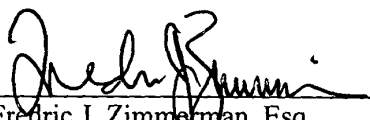
	<u>AFTER AMENDMENT</u>	<u>PREV. PAID FOR</u>	<u>EXTRA CLAIMS PRESENT</u>	<u>RATE</u>	<u>FEE DUE</u>
Total Claims	27 -	21	= 6	x \$18.00	\$ 108.00
Indep. Claims	3 -	3	= 1	x \$84.00	\$ -
TOTAL ADDITIONAL FEE FOR THIS AMENDMENT					\$ 108.00

A check in the amount of \$108.00 is submitted herewith to cover the excess claim fees. A duplicate copy of this sheet is enclosed. The Commissioner is authorized to charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 50-0481.

Respectfully Submitted,

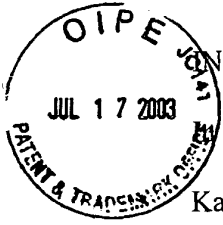
Date:

7/17/03


Fredric J. Zimmerman, Esq.
Reg. No. 48,747

McGinn & Gibb, PLLC
8321 Old Courthouse Road, Suite 200
Vienna, VA 22182
(703) 761-4100
Customer No.: 21254

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re Application of

Kazuki Yokota

Serial No.: 09/627,456

Group Art Unit: 2851

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METHOD OF MAKING ALIGNMENT AND SEMICONDUCTOR DEVICE
THEREWITH

Honorable Commissioner of Patents
Alexandria, Virginia 22313-1450

AMENDMENT UNDER 37 C.F.R. §1.111

Sir:

In response to the Office Action dated **April 23, 2003**, please amend the above-
identified application as follows:

07/18/2003 RMQNDAF1 00000086 09627456

01 FC:1202

108.00 0P

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